PHB32N06LT

N-channel TrenchMOS logic level FET

Rev. 02 — 30 November 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

 Suitable for logic level gate drive sources

1.3 Applications

General purpose switching

Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	60	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 5 V; see <u>Figure 1</u> and <u>3</u>	-	-	34	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	97	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 20 \text{ A};$ $V_{DS} = 44 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 11	-	8.5	-	nC
Static ch	naracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 20 \text{ A};$ $T_j = 25 \text{ °C}$	-	31.5	43	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 20 \text{ A};$ $T_j = 25 \text{ °C};$ see Figure 9 and 10	-	30	40	mΩ



2. Pinning information

Table 2. Pinning information

	_				
Pin	Symbol	Description		Simplified outline	Graphic symbol
1	G	gate			
2	D	drain	<u>[1]</u>	mb	D
3	S	source			
mb	D	mounting base; connected to drain		1 3	mbb076 S
				SOT404 (D2PAK)	

[1] It is not possible to make a connection to pin 2.

3. Ordering information

Table 3. Ordering information

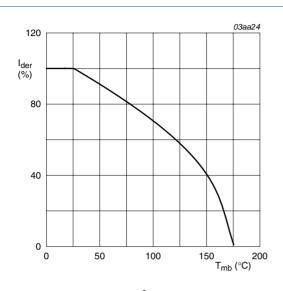
Type number	Package						
	Name	Description	Version				
PHB32N06LT	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404				

4. Limiting values

Table 4. Limiting values

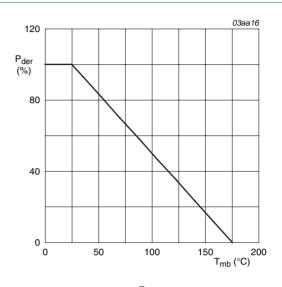
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	60	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	60	V
V_{GS}	gate-source voltage		-15	15	V
I _D	drain current	V _{GS} = 5 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	24	Α
		$V_{GS} = 5 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{1}} \text{ and } \frac{3}{\text{2}}$	-	34	Α
I _{DM}	peak drain current	$t_p \le 10$ μs; pulsed; $T_{mb} = 25$ °C; see Figure 3	-	136	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	97	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
V_{GSM}	peak gate-source voltage	pulsed; $t_p \le 50 \mu s$	-20	20	V
Source-dr	rain diode				
Is	source current	$T_{mb} = 25 ^{\circ}\text{C}$	-	34	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	136	Α
Avalanche	e ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 5 V; $T_{j(init)}$ = 25 °C; I_D = 20 A; V_{sup} ≤ 25 V; unclamped; t_p = 0.11 ms; R_{GS} = 50 Ω	-	100	mJ



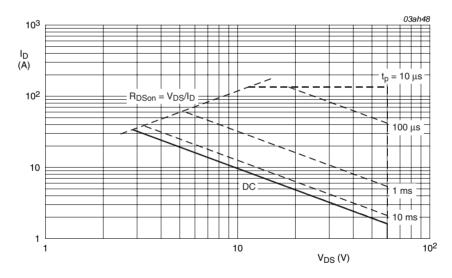
$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{amb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Characteristics

Table 5. Characteristics

Table 5.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	55	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	60	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 8	-	-	2.3	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ °C}$; see Figure 8	1	1.5	2	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see Figure 8	0.5	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
		$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
I_{GSS}	gate leakage current	$V_{GS} = 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		$V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R _{DSon}	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 20 \text{ A}; T_j = 25 \text{ °C}$	-	31.5	43	mΩ
resistance	resistance	$V_{GS} = 5 \text{ V}; I_D = 20 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 9 and 10	-	-	84	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 20 \text{ A}; T_j = 25 \text{ °C}$	-	26	37	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 20 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9 and 10	-	30	40	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 20 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 5 \text{ V};$	-	17	-	nC
Q_{GS}	gate-source charge	$T_j = 25$ °C; see Figure 11	-	3	-	nC
Q_{GD}	gate-drain charge		-	8.5	-	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	920	1280	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	160	200	pF
C _{rss}	reverse transfer capacitance		-	100	155	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 5 \text{ V};$	-	14	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	120	-	ns
t _{d(off)}	turn-off delay time		-	45	-	ns
t _f	fall time		-	55	-	ns
Source-di	ain diode					
V_{SD}	source-drain voltage	I_S = 25 A; V_{GS} = 0 V; T_j = 25 °C; see <u>Figure 7</u>	-	1	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = -10 \text{ V}$;	-	36	-	ns
Q _r	recovered charge	$V_{DS} = 30 \text{ V; } T_j = 25 ^{\circ}\text{C}$	-	70	-	nC

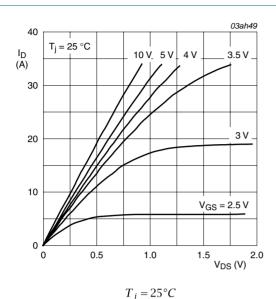
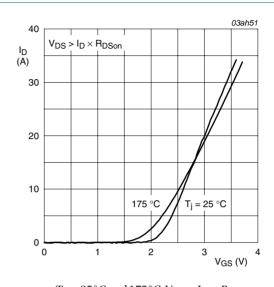
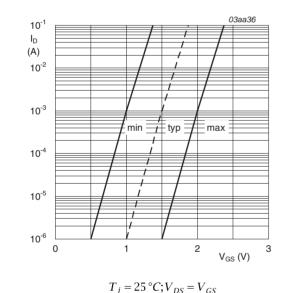


Fig 4. Output characteristics: drain current as a function of drain-source voltage; typical values

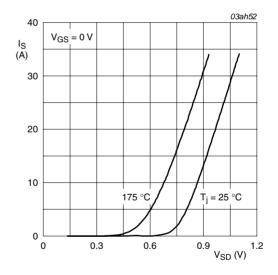


 $T_i = 25$ °C and 175°C; $V_{DS} > I_D \times R_{DSon}$

Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values

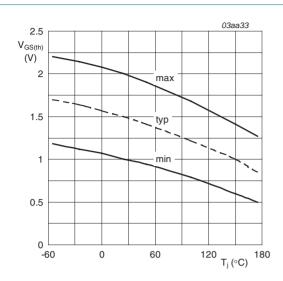


Sub-threshold drain current as a function of Fig 6. gate-source voltage



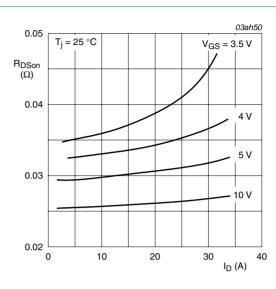
 $T_i = 25^{\circ} C$ and $175^{\circ} C$; $V_{GS} = 0V$

Fig 7. Source current as a function of source-drain voltage; typical values



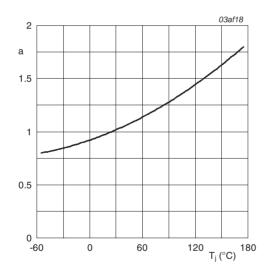
 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 8. Gate-source threshold voltage as a function of junction temperature



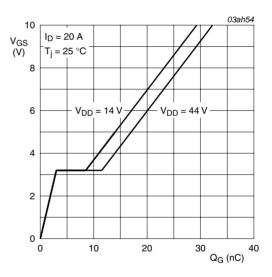
 $T_j = 25^{\circ}C$

Fig 9. Drain-source on-state resistance as a function of drain current; typical values



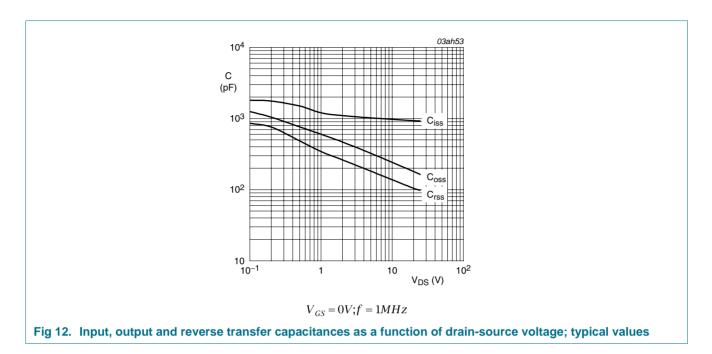
 $a = \frac{R_{DSon}}{R_{DSon(2.5^{\circ}C)}}$

Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature



$$T_j = 25^{\circ}C; I_D = 20A$$

Fig 11. Gate-source voltage as a function of turn-on gate charge; typical values



6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 13	-	-	1.55	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on printed-circuit board; minimum footprint	-	50	-	K/W

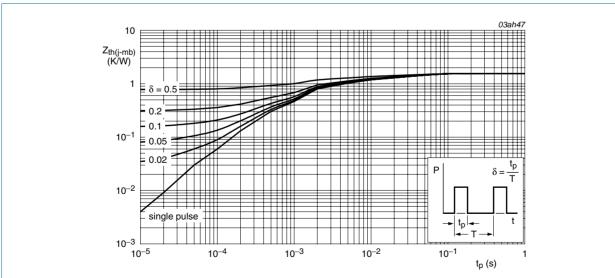
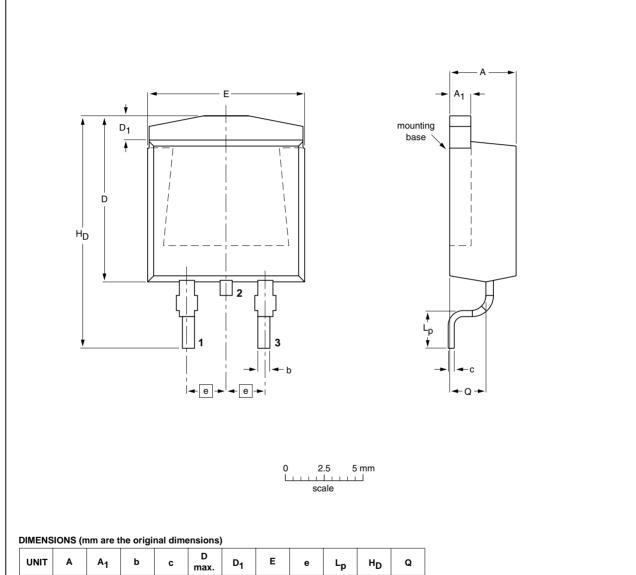


Fig 13. Transient thermal impedance from junction to mounting base as a function of pulse duration

7. Package outline

Plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)

SOT404



UN	NIT	A	A ₁	b	С	D max.	D ₁	E	е	L _p	Н _D	Q
m	m	4.50 4.10	1.40 1.27	0.85 0.60	0.64 0.46	11	1.60 1.20	10.30 9.70	2.54	2.90 2.10	15.80 14.80	2.60 2.20

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT404						05-02-11 06-03-16

Fig 14. Package outline SOT404 (D2PAK)



8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes			
PHB32N06LT_2	20091130	Product data sheet	-	PHP_PHB_32N06LT-01			
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 						
	 Legal texts have been adapted to the new company name where appropriate. 						
PHP_PHB_32N06LT-01 (9397 750 09024)	20011106	Product data	-	-			

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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PHB32N06LT

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11. Contents

1	Product profile
1.1	General description
1.2	Features and benefits1
1.3	Applications1
1.4	Quick reference data1
2	Pinning information2
3	Ordering information2
4	Limiting values2
5	Characteristics4
6	Thermal characteristics7
7	Package outline8
8	Revision history9
9	Legal information10
9.1	Data sheet status
9.2	Definitions10
9.3	Disclaimers
9.4	Trademarks10
10	Contact information10

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